

Part Number

Customer

| Category | Parameter | Specification | Measurement Method | |
|---------------|-----------|---|------------------------------------|---------------------------------|
| OverallWafer | 1.0 | Diameter | 100.00 +/- 0.50 mm | |
| | 2.0 | Primary Flat Orientation | {110} +/- 0.5 degree | Wafer Vendor |
| | 3.0 | Primary Flat Length | 32.50 +/- 2.50 mm | Wafer Vendor |
| | 4.0 | Secondary Flat Orientation | none | Wafer Vendor |
| | 5.0 | Overall Thickness | 442.00 +/- 16.00 µm | ADE, 100% |
| | 6.0 | Total Thickness Variation (TTV) | <5.00µm | Guaranteed by Process |
| | 7.0 | Bow | <60.00µm | Estimate ADE to ASTM F534, 100% |
| | 8.0 | Warp | <60.00µm | Estimate ADE to ASTM F534, 100% |
| | 9.0 | Edge Chips | 0 | Bright Light, 100% |
| | 10.0 | Edge Exclusion | 5mm | |
| HandleSilicon | 11.0 | Handle Growth Method | CZ | Wafer Vendor |
| | 12.0 | Handle Orientation | {100} +/- 0.5 degree | Wafer Vendor |
| | 13.0 | Handle Thickness | 400.00 +/- 15.00 µm | ADE, 100% |
| | 14.0 | Handle Doping Type | N | Wafer Vendor |
| | 15.0 | Handle Dopant | Phosphorus | Wafer Vendor |
| | 16.0 | Handle Resistivity | 1~10 Ohmcm | Wafer Vendor |
| | 17.0 | Backside Finish | Polished with lasermark and oxide. | Guaranteed by process |
| BuriedOxide | 18.0 | Oxide Type | Thermal | |
| | 19.0 | Oxide Thickness | 20,000.00 +/- 1,000.00 A | Nanospec centre point, 4% |
| | 20.0 | Oxide formed on | Handle | |
| DeviceSilicon | 21.0 | Device Growth Method | CZ | Wafer Vendor |
| | 22.0 | Device Orientation | {100} +/- 0.5 degree | Wafer Vendor |
| | 23.0 | Nominal Thickness | 40.00 +/- 1.00 µm | Single point ADE, 100% (note3) |
| | 24.0 | Distance to device silicon edge from wafer edge | < 2mm | Typical by Process |
| | 25.0 | Device Doping Type | N | Wafer Vendor |
| | 26.0 | Device Dopant | Phosphorus | Wafer Vendor |
| | 27.0 | Device Resistivity | <0.005 Ohmcm | Wafer Vendor |
| | 28.0 | Surface Voids | None | Bright Light, 100% (note2) |
| | 29.0 | Haze | None | Bright Light, 100% (note2) |
| | 30.0 | Scratches | none on the front-side | Bright Light, 100% (note2) |

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|------------------|-------------------|---|
| Shipping Details | Wafer per box : | Max 25 |
| | Packaging : | Taped Polypropylene Wafer Box Empak, Ultrapak, 100.00mm Antistatic Double Bagging |
| | Lot Shipment Data | Device Thickness Bow / Warp Data Handle and SOI Thickness |



Explanatory Notes 1. Microscope inspection performed using microscope scan as below. 5x objective.

2. All bright light inspections performed exclude all wafer area outside the edge exclusion defined in Overall Wafer, Edge Exclusion. High intensity bright lamp inspection as per ASTM F523.

3. 9 point measurement are as shown in the diagram below:



Additional Information